

FIG. 1

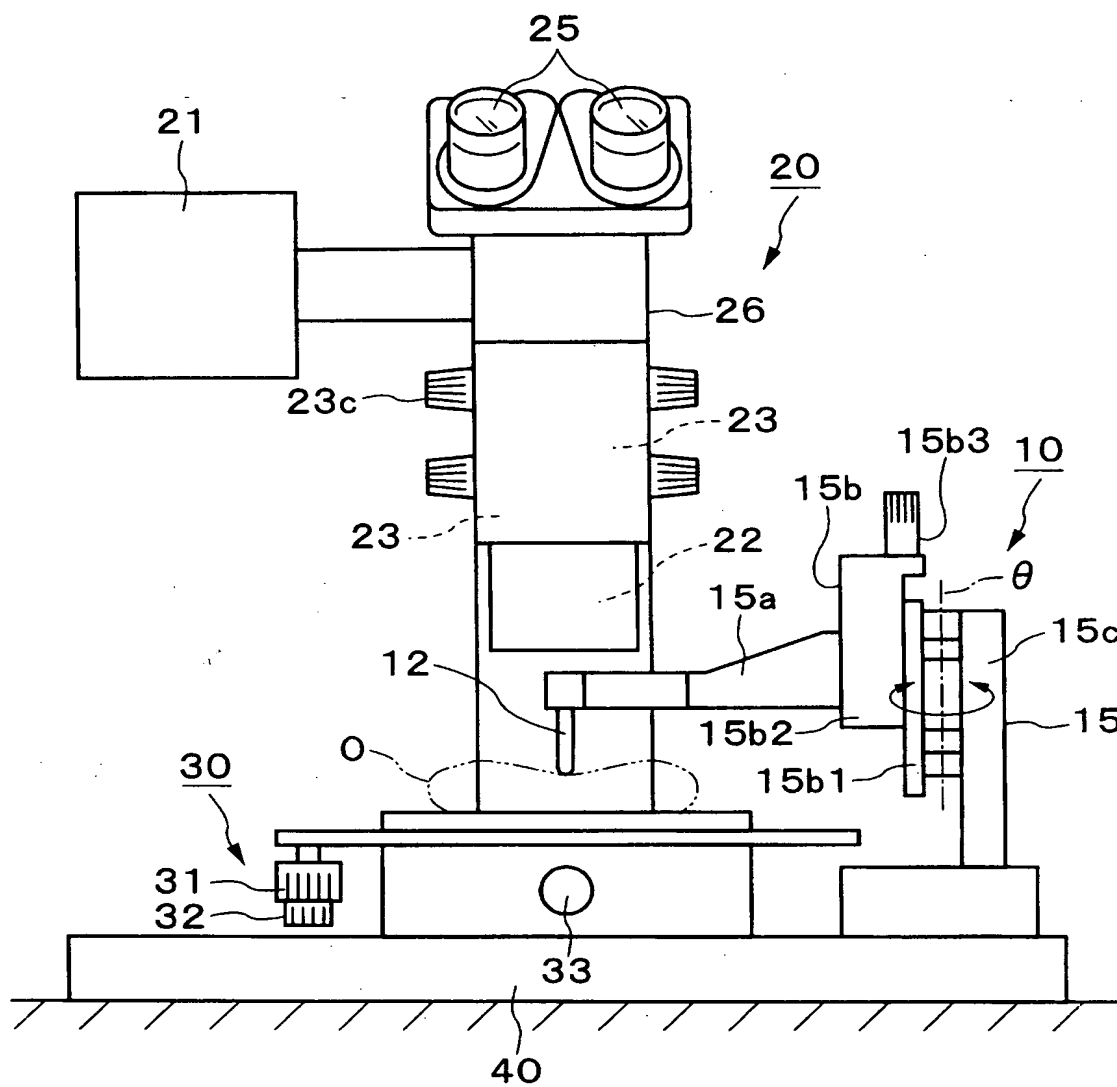


FIG. 2

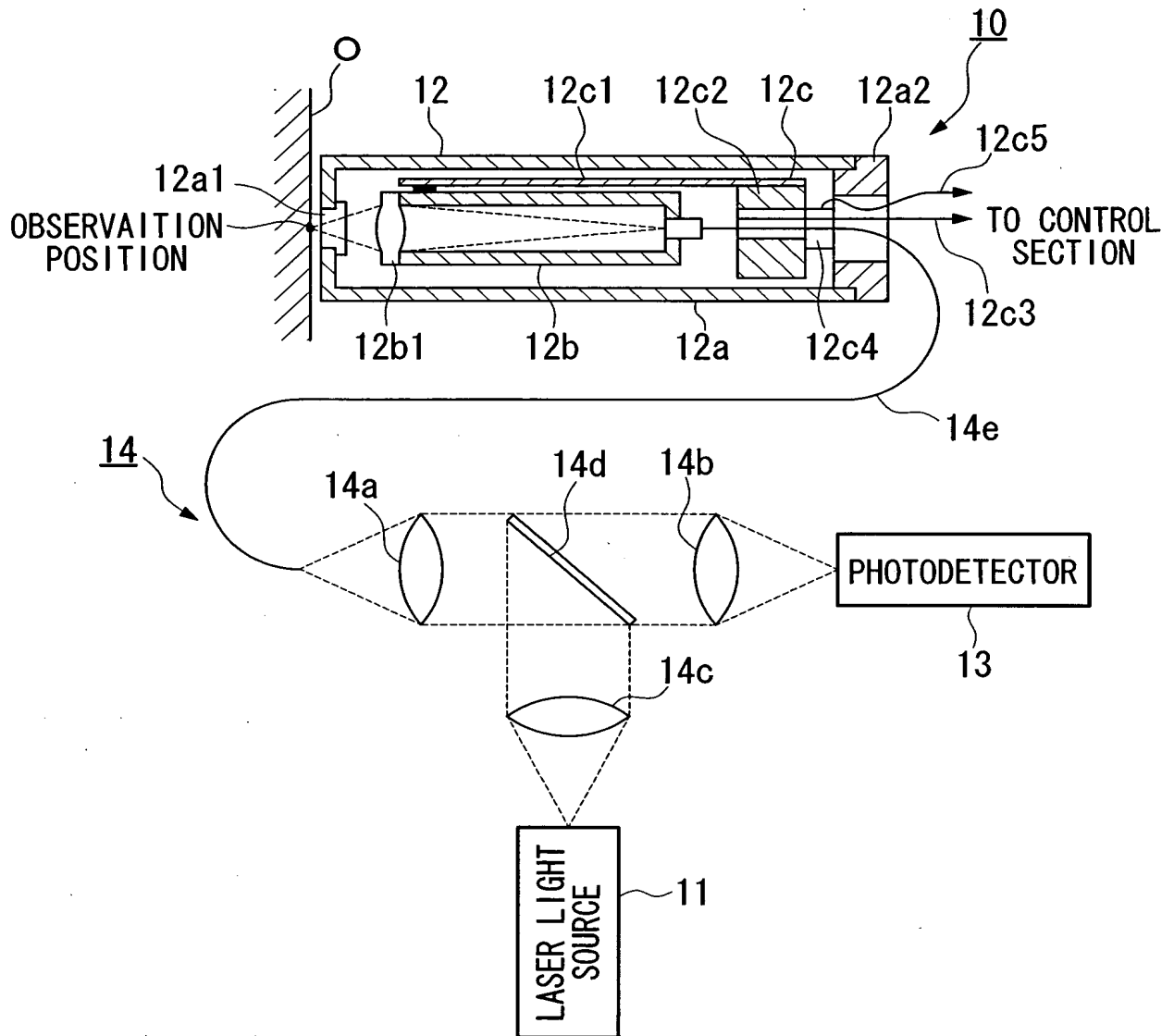


FIG. 3

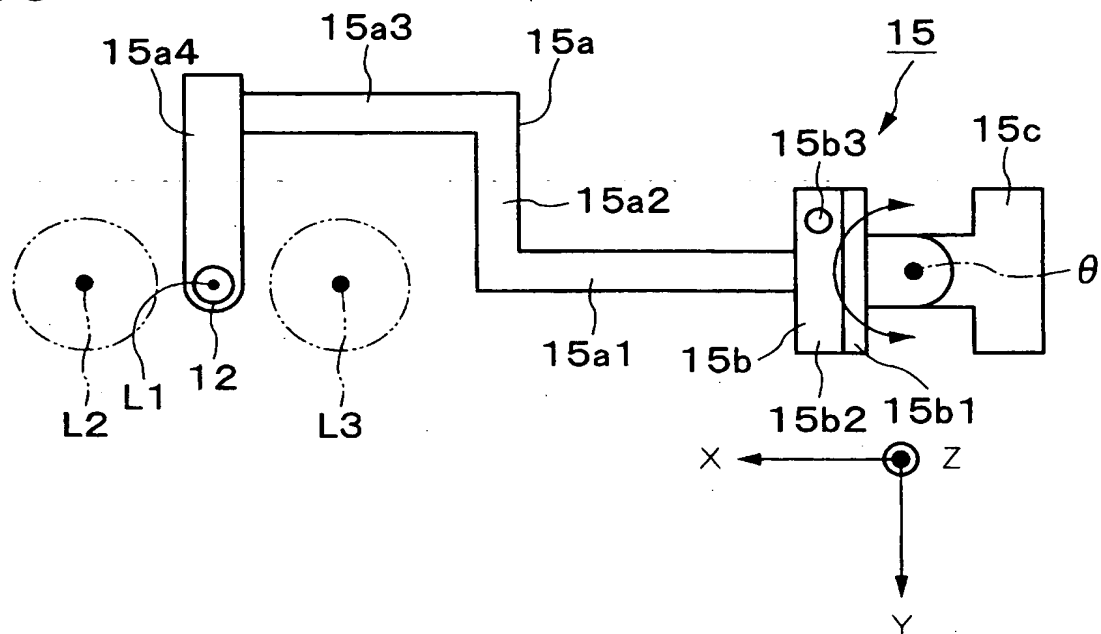


FIG. 4

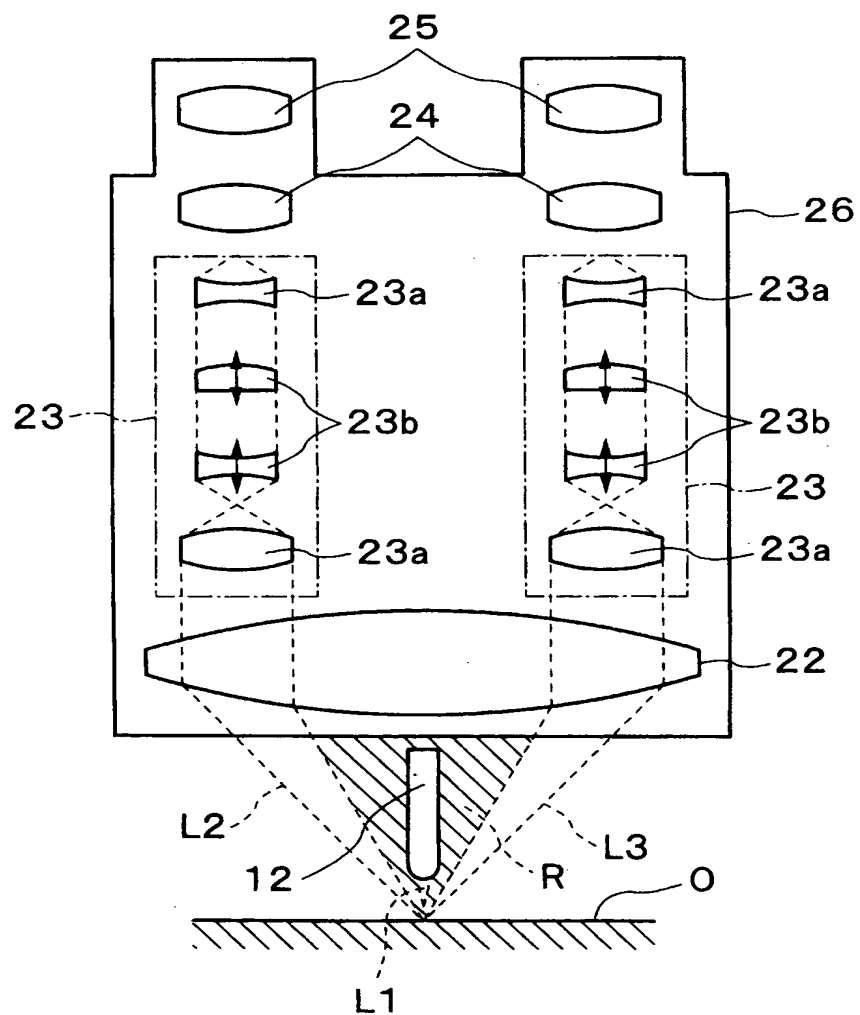


FIG. 5

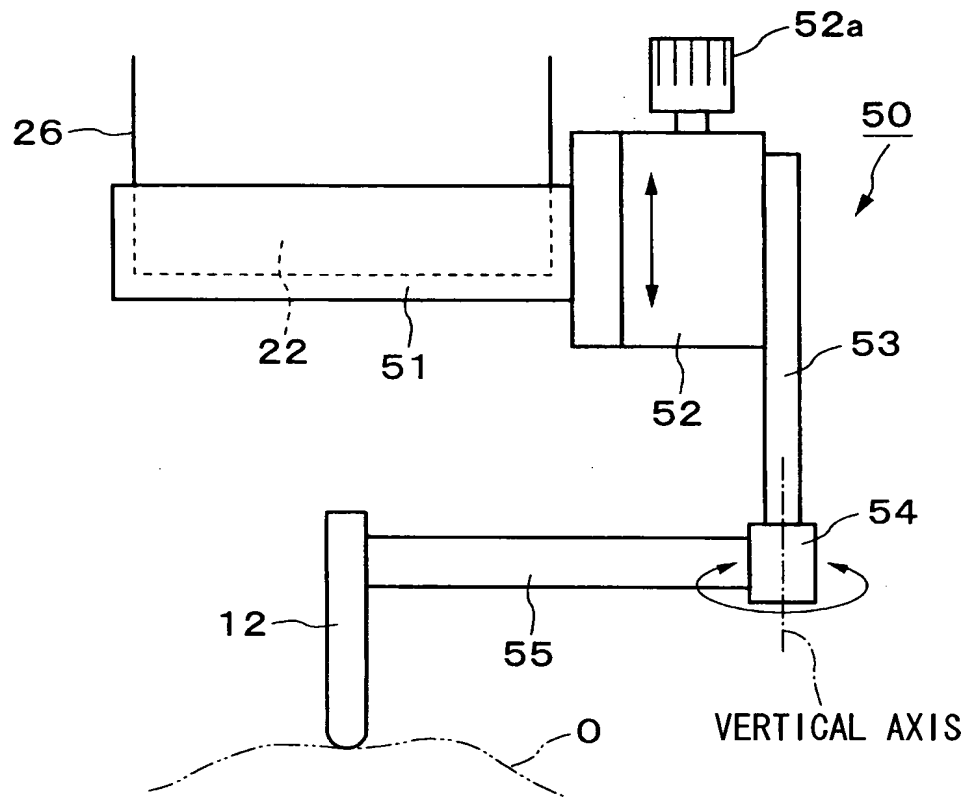


FIG. 6A

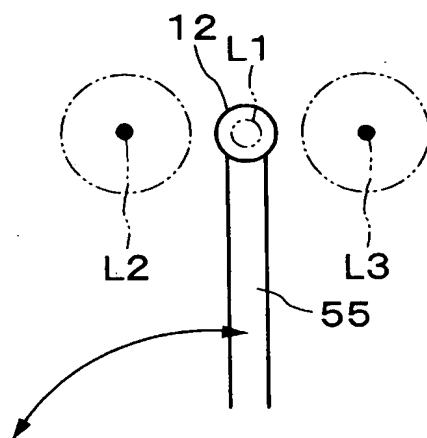


FIG. 6B

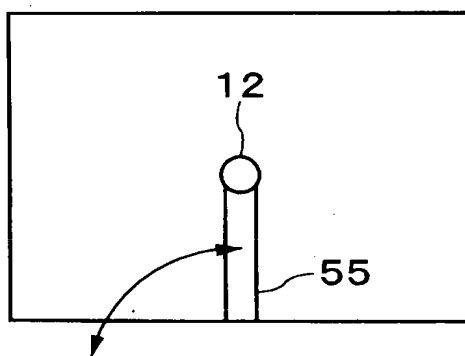


FIG. 7

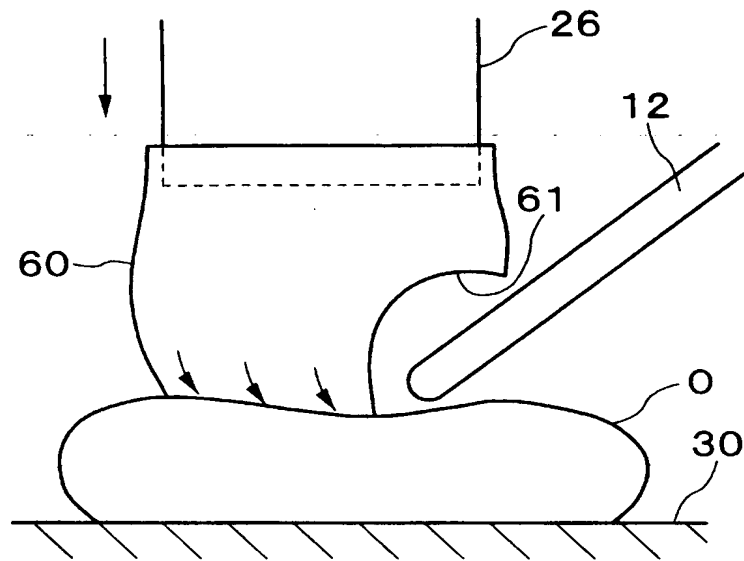


FIG. 8

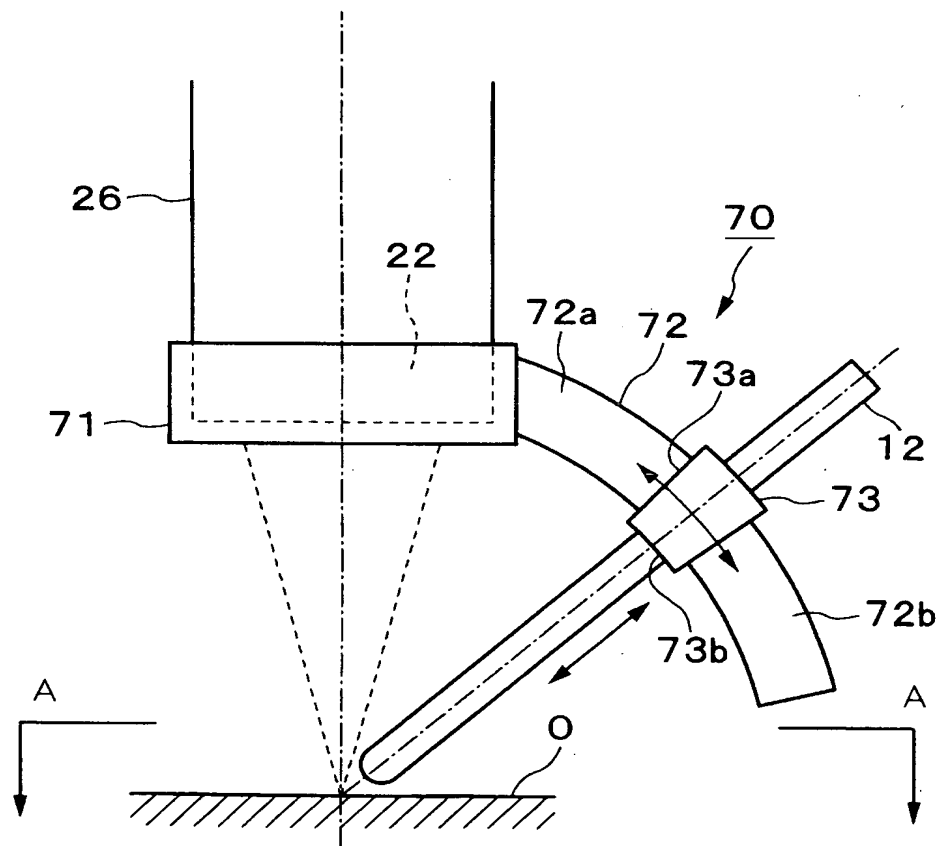


FIG. 9

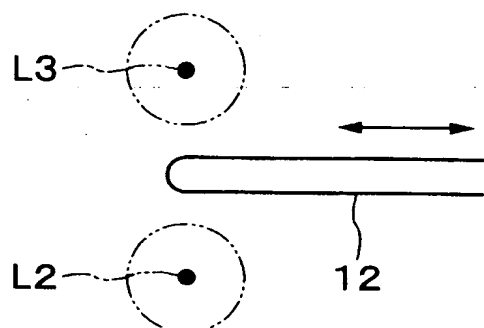


FIG. 10

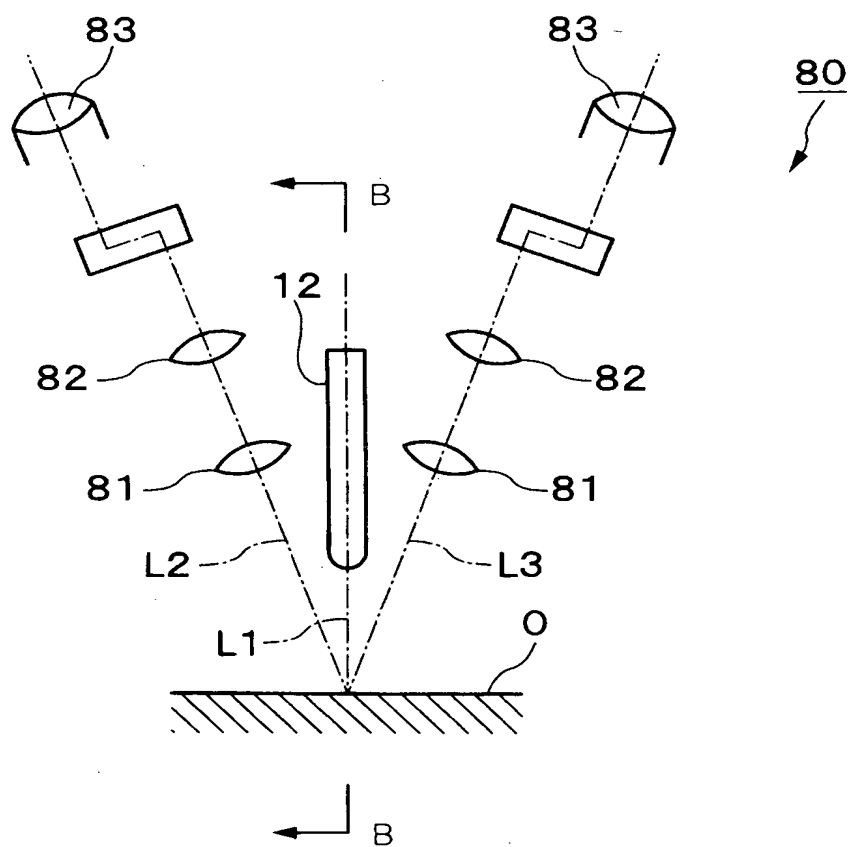


FIG. 11A

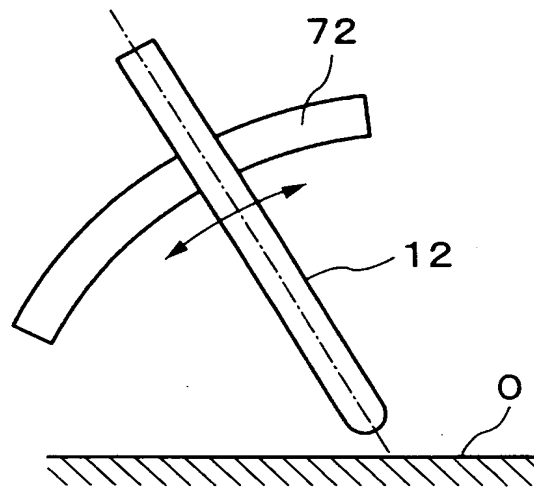


FIG. 11B

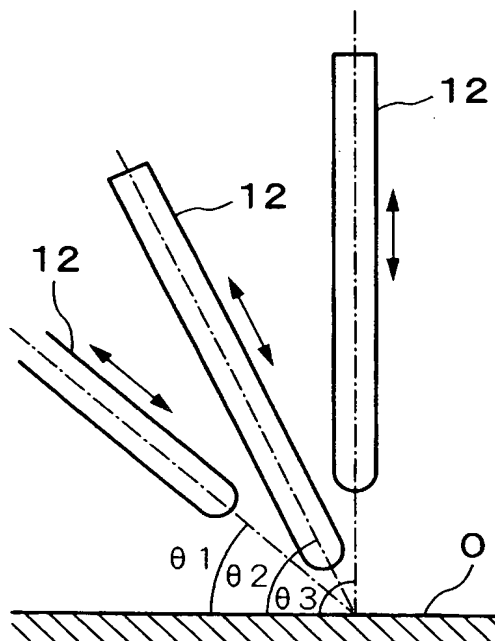




FIG. 12

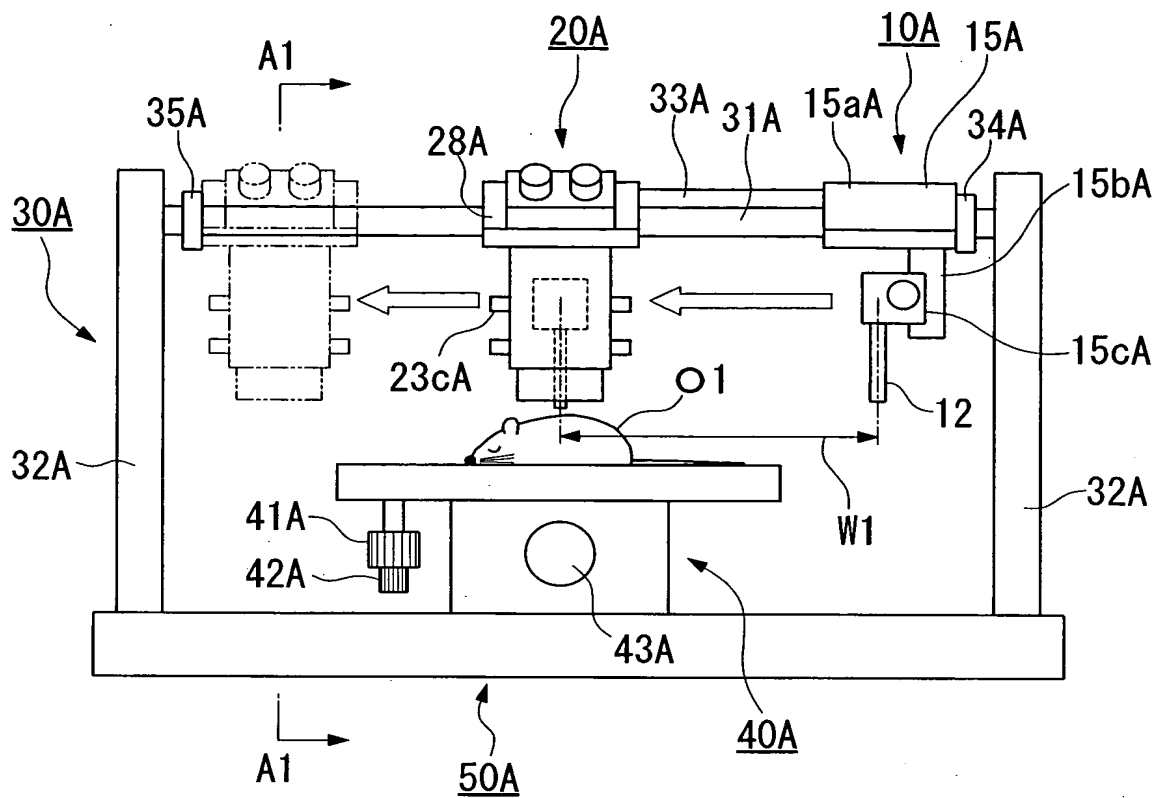


FIG. 13

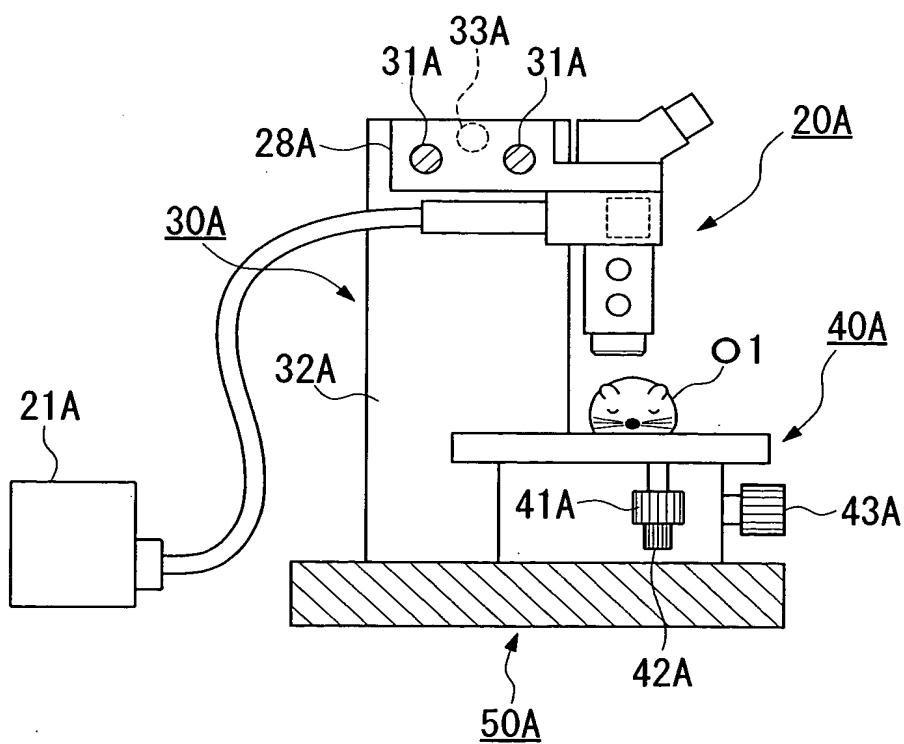


FIG. 14

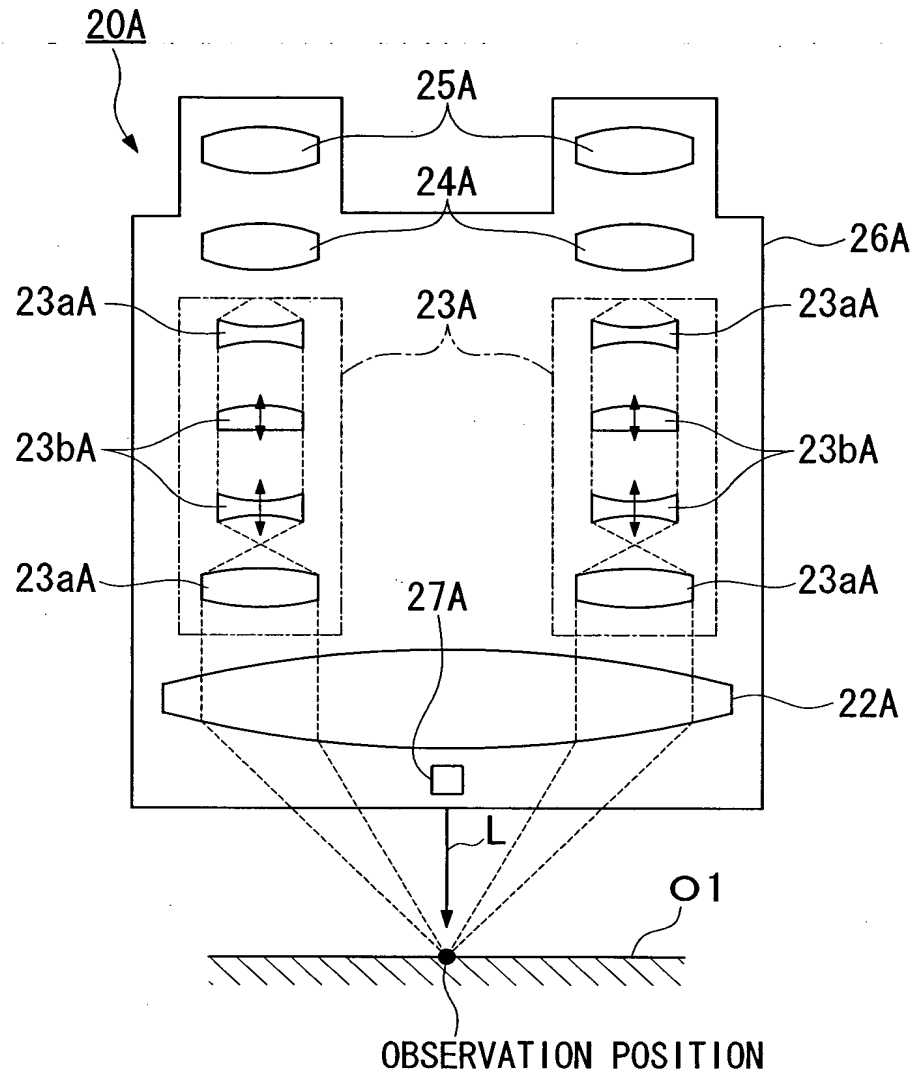


FIG. 15

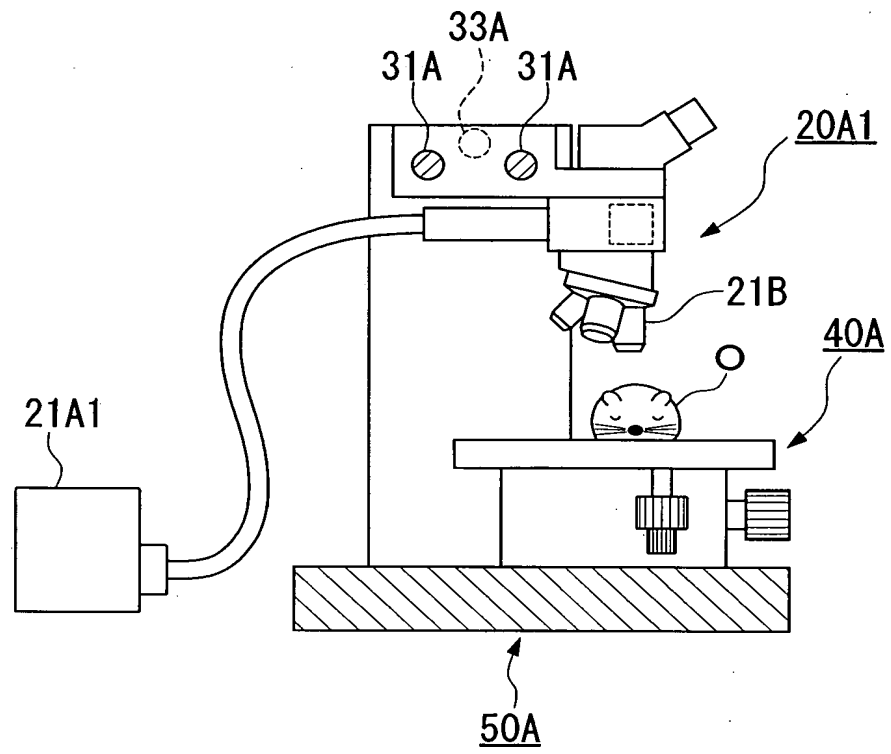


FIG. 16

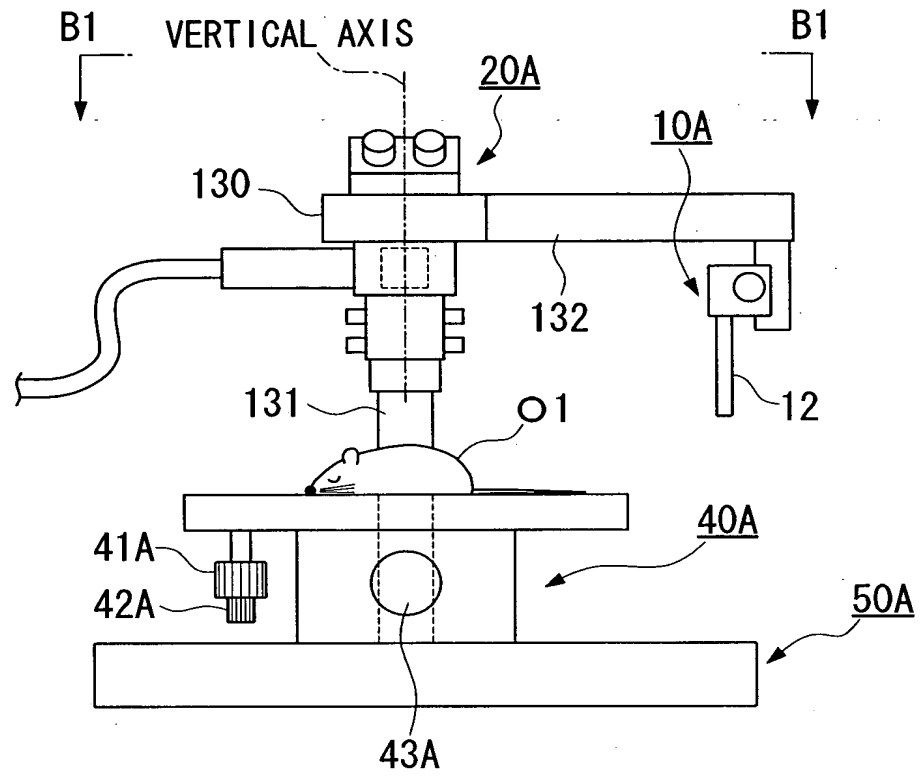


FIG. 17

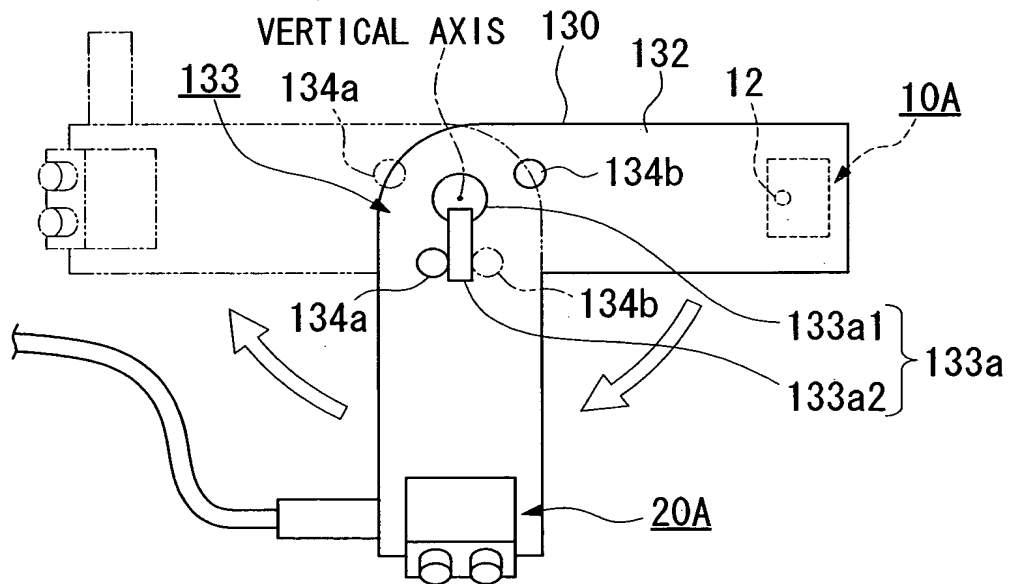


FIG. 18

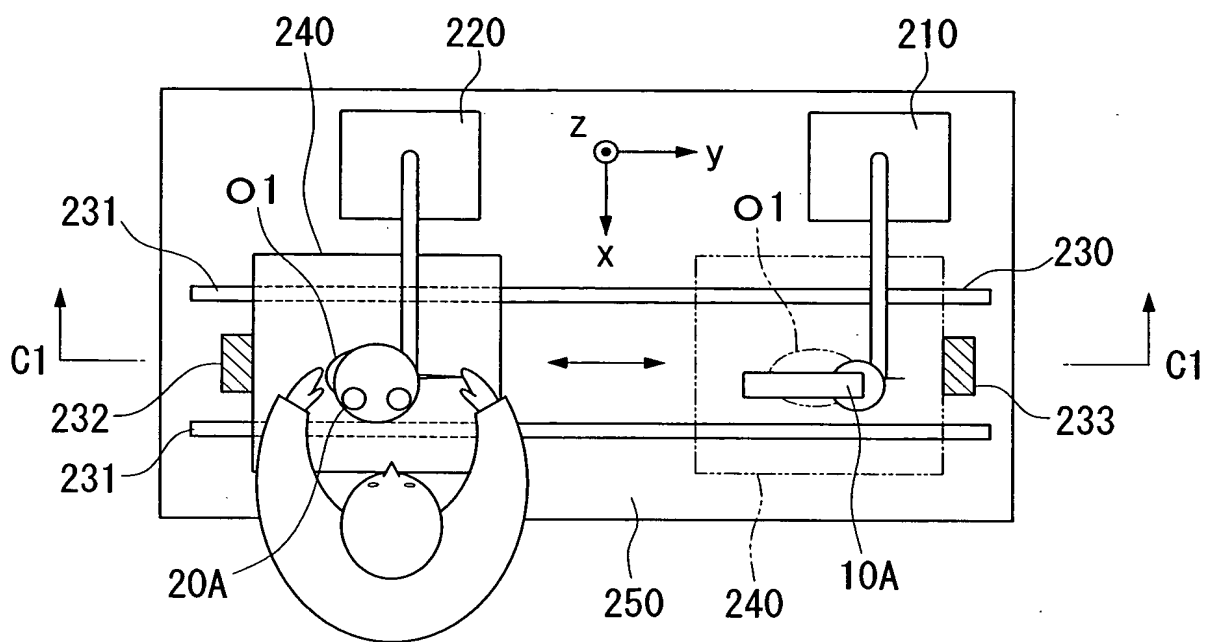


FIG. 19

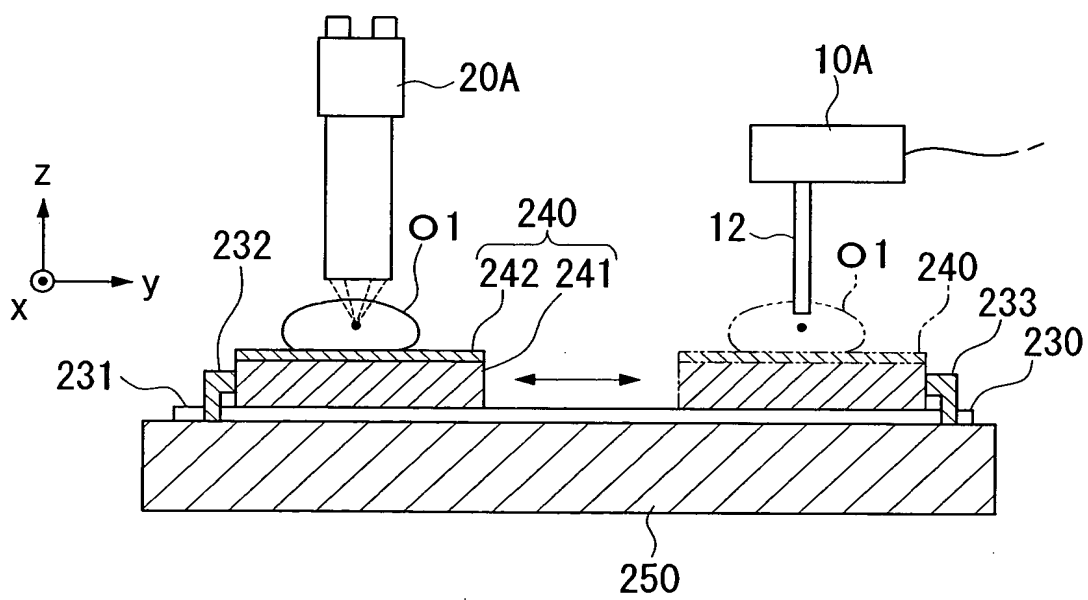


FIG. 20

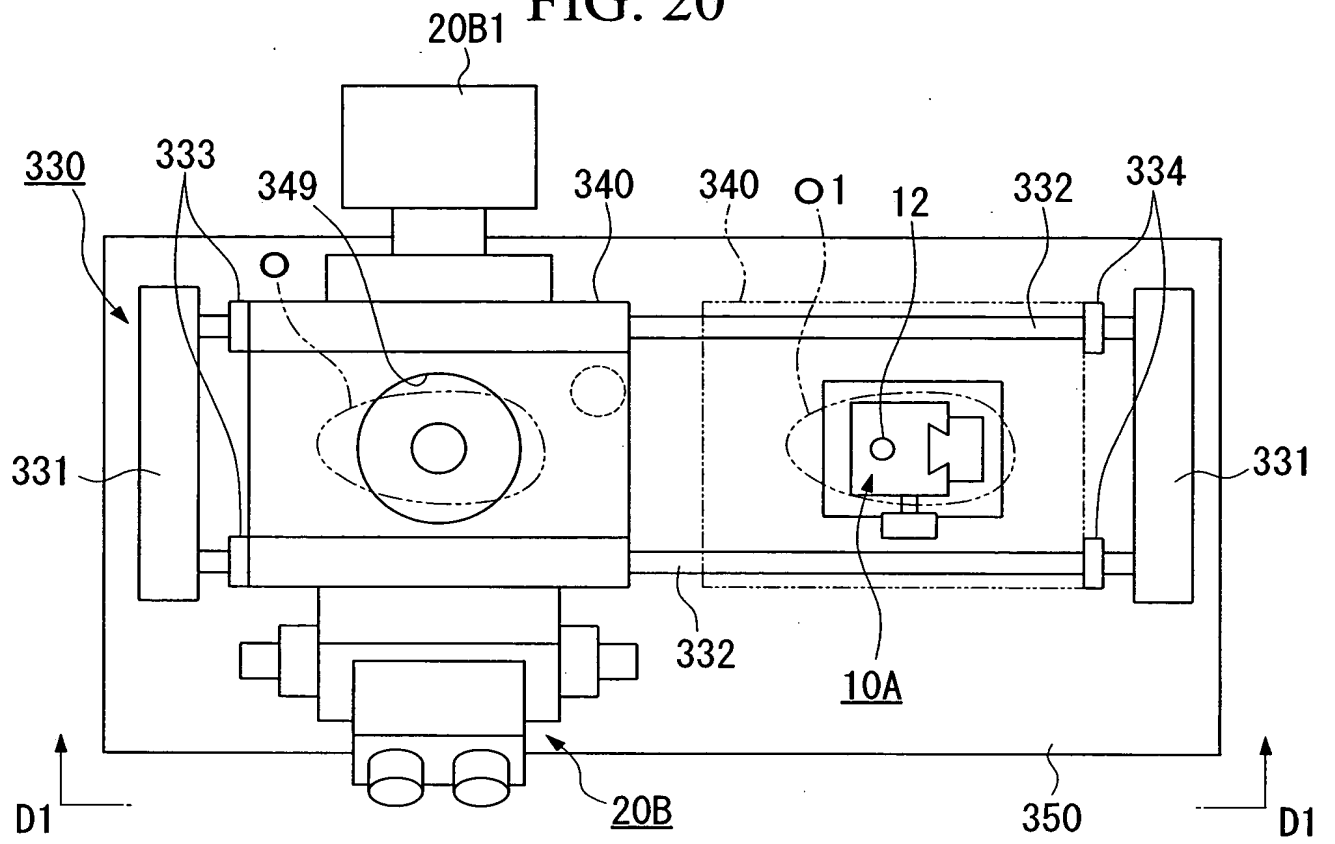


FIG. 21

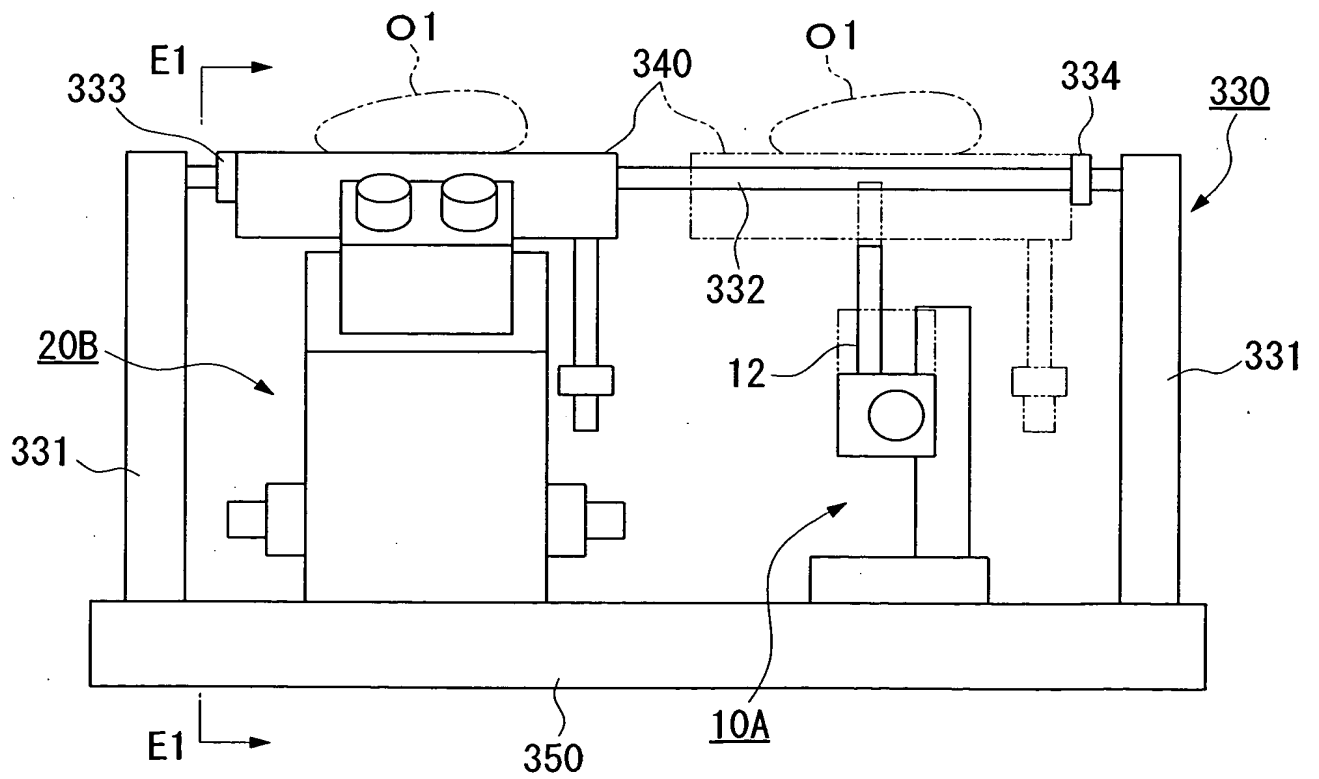


FIG. 22

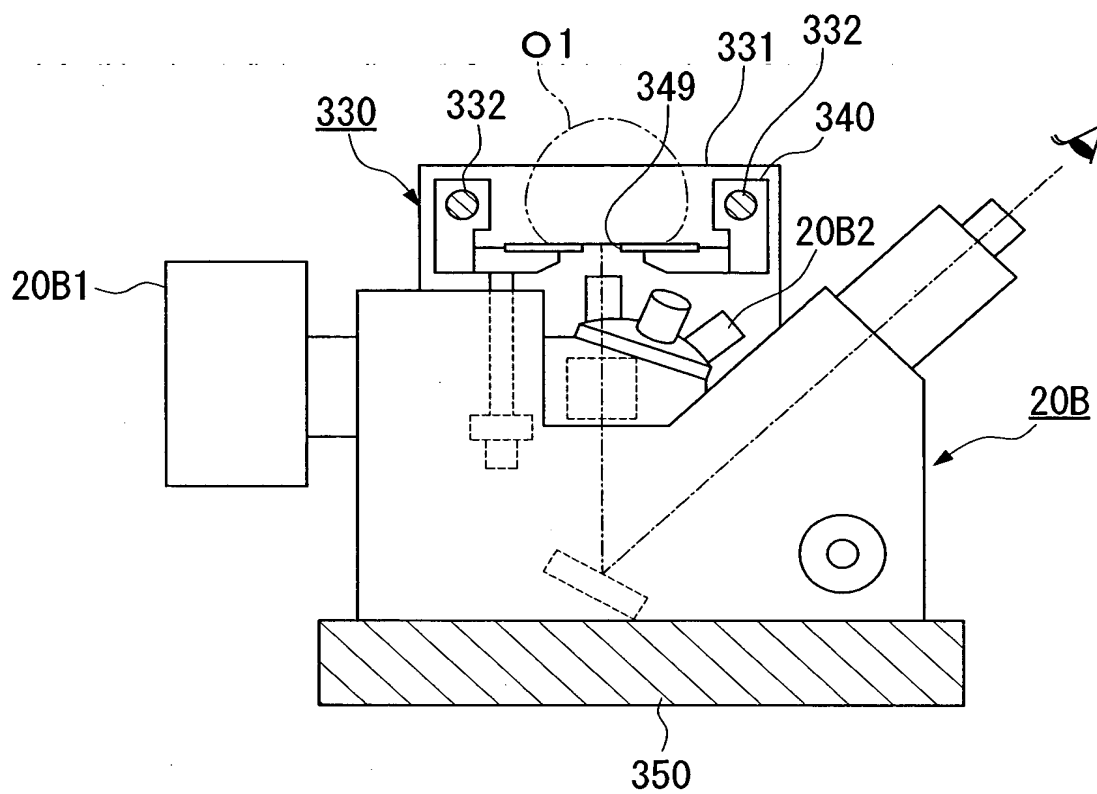


FIG. 23

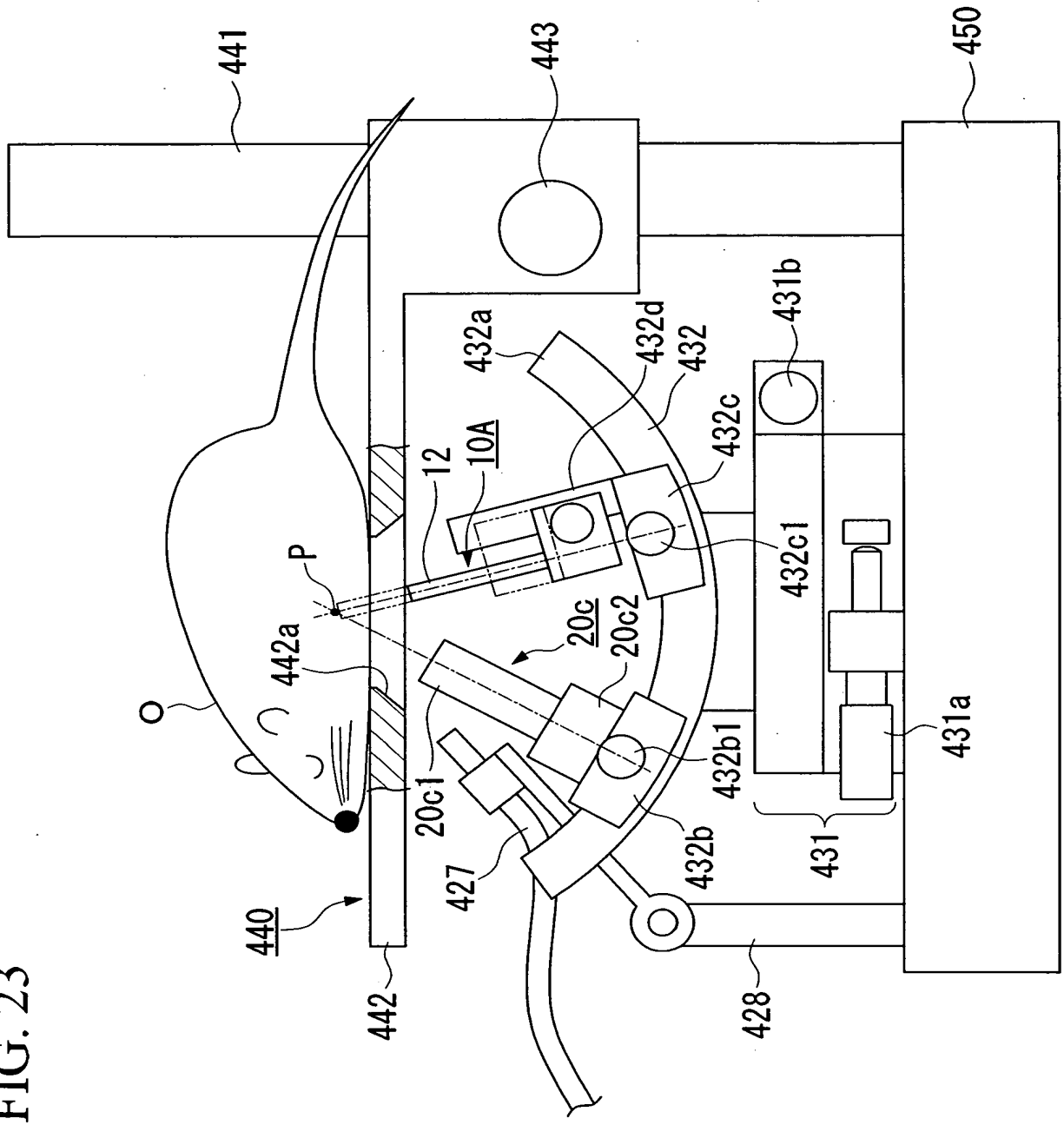




Diagram illustrating a measurement system 10A. The system includes a probe 12 positioned above a sample 40A. The probe is mounted on a vertical support 521, which is part of a larger assembly 520. The assembly 520 includes a horizontal arm 523 and a vertical guide 522. The probe 12 is connected to the horizontal arm 523 via a joint 524. The probe 12 is shown in a tilted position, with its tip 12a pointing towards the sample 40A. The diagram also shows a horizontal axis and a  $\theta$  AXIS for rotation.

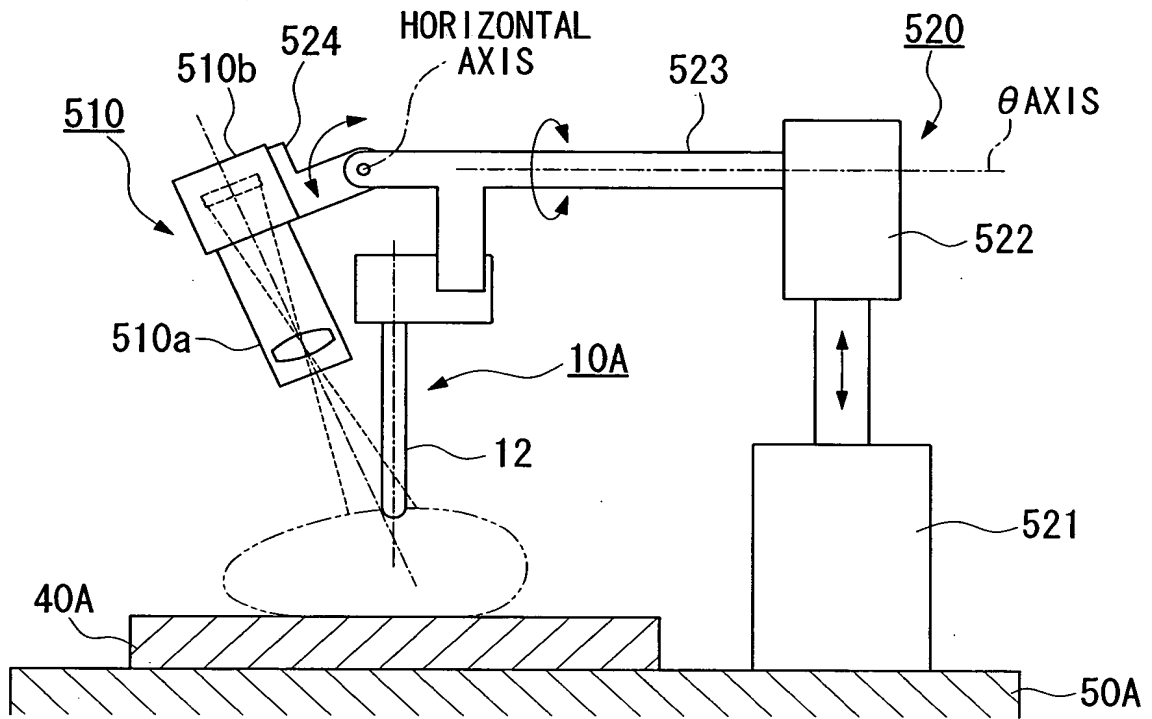


FIG. 25

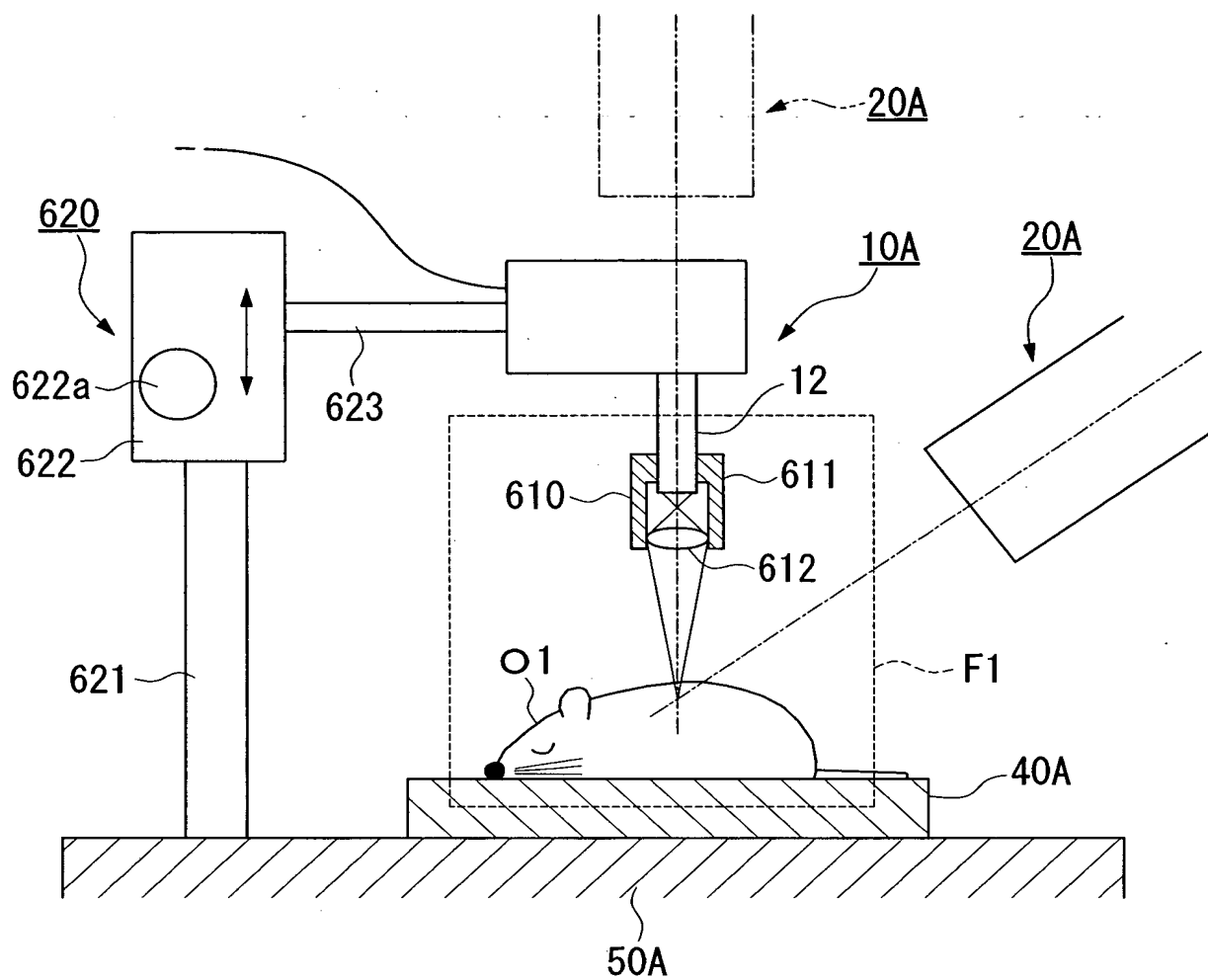


FIG. 26

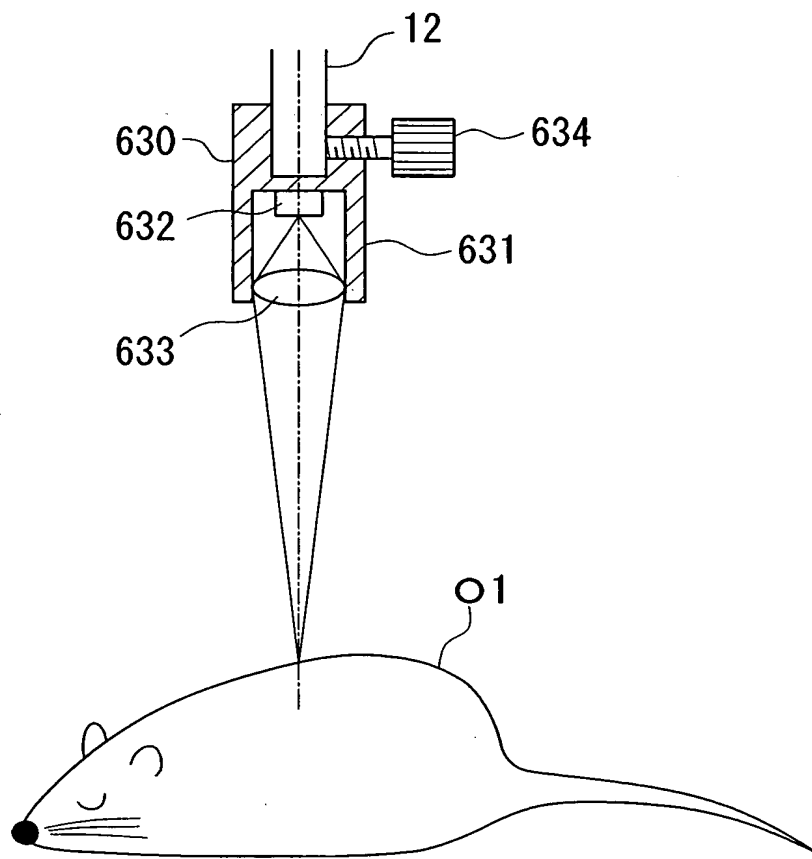


FIG. 27

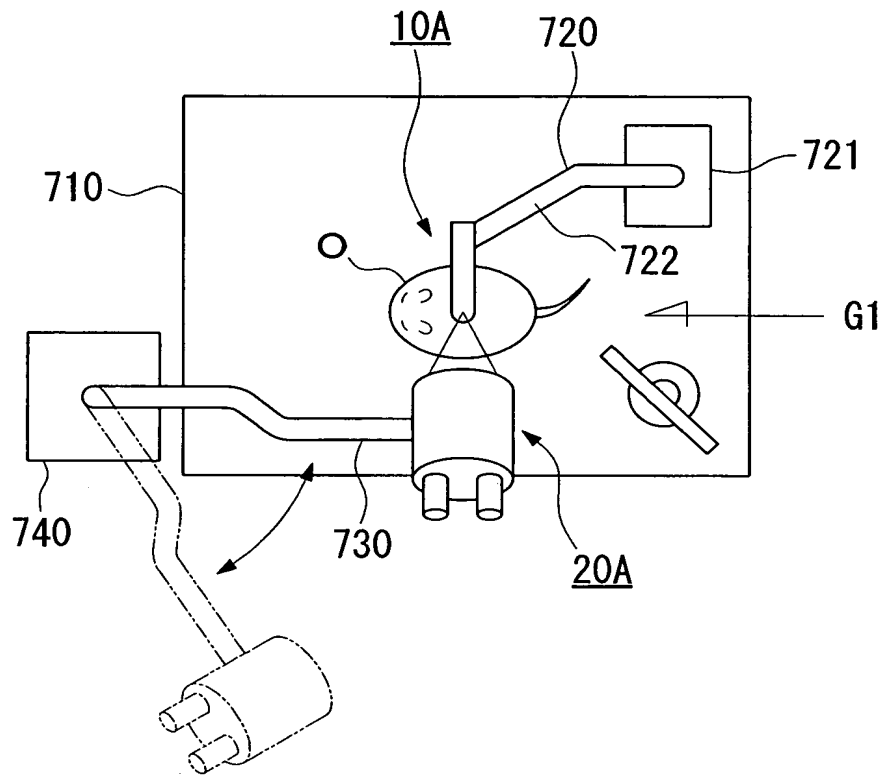


FIG. 28

